

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

et No.: 10559-587001 / P12768

Applicant: Been-Yih Jin et al.

Art Unit: 2812

Serial No.: 10/081,992

Examiner: Ron E. Pompey

Filed Title

: February 21, 2002

Confirmation No.: 1734

: NON-SILICON SEMICONDUCTOR AND HIGH-K GATE DIELECTRIC

METAL OXIDE SEMICONDUCTOR FIELD EFFECT TRANSISTORS

Commissioner for Patents Washington, D.C. 20231

<u>AMENDMENT</u>

In response to the Office Action dated November 21, 2002, please amend the aboveidentified application as follows:

IN THE CLAIMS:

Please amend claims 8, 16, and 19 as follows:

FECHNOLOGY CENTER \$800

-- 8. (Amended) A transistor comprising:

a semiconductor substrate, the substrate being substantially free of silicon; and

a gate dielectric layer formed over a portion of the substrate, wherein the gate dielectric comprises a material having a dielectric constant greater than about 10.

CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, Washington, D.C. 20231.

February 21.

Date of

Melissa K. Addis

Typed or Printed Name of Person Signing Certificate